

# **4Gb NAND FLASH**

## **HY27UT084G2M**

**Document Title**  
**4Gbit (512Mx8bit) NAND Flash Memory**

**Revision History**

Revision No.	History	Draft Date	Remark															
0.0	Initial Draft.	Dec. 29.2004	Preliminary															
0.1	1) Delete Double Page Program - Texts & Figures are deleted. 2) Delete Copy-back Operation figure 3) Correct Program Time (tPROG) <table border="1" style="margin-left: 20px;"> <thead> <tr> <th>tPROG</th> <th>Typ.</th> <th>Max.</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>1200us</td> <td>2000us</td> </tr> <tr> <td>After</td> <td>600us</td> <td>800us</td> </tr> </tbody> </table>	tPROG	Typ.	Max.	Before	1200us	2000us	After	600us	800us	Apr. 15. 2005	Preliminary						
tPROG	Typ.	Max.																
Before	1200us	2000us																
After	600us	800us																
0.2	1) Change AC Conditions table 2) Add tWW parameter ( tWW = 100ns, min) - Texts & Figures are added. - tWW is added in AC timing characteristics table. 3) Edit System Interface Using $\overline{CE}$ don't care. 4) Correct Program Time (tRPOG) <table border="1" style="margin-left: 20px;"> <thead> <tr> <th>tPROG</th> <th>Typ.</th> <th>Max.</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>600us</td> <td>800us</td> </tr> <tr> <td>After</td> <td>800us</td> <td>2000us</td> </tr> </tbody> </table> 5) Correct Address Cycle Map. 6) Add Read ID table 7) Correct PKG dimension (TSOP PKG) <table border="1" style="margin-left: 20px;"> <thead> <tr> <th></th> <th>CP</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>0.050</td> </tr> <tr> <td>After</td> <td>0.100</td> </tr> </tbody> </table> 8) Delete ECC	tPROG	Typ.	Max.	Before	600us	800us	After	800us	2000us		CP	Before	0.050	After	0.100	Oct. 12. 2005	Preliminary
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Before	600us	800us																
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	CP																	
Before	0.050																	
After	0.100																	
0.3	1) Delete Auto Read Page 0 function. - The texts & figures are deleted. - The definition of PRE is deleted. 2) Correct DC Characteristics. (Table 9) 3) Add ECC algorithm. (4bit/512byte) 4) Delete Cache Program function - The texts & figures are deleted.	Dec. 23. 2005	Preliminary															

Revision History

-Continued-

Revision No.	History	Draft Date	Remark																																																												
0.4	<p>1) Change AC timing characteristics</p> <table border="1"> <thead> <tr> <th></th> <th>tWP</th> <th>tWH</th> <th>tWC</th> <th>tALS</th> <th>tALH</th> <th>tDH</th> <th>tR</th> <th>tAR</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>25</td> <td>15</td> <td>50</td> <td>0</td> <td>10</td> <td>10</td> <td>50</td> <td>10</td> </tr> <tr> <td>After</td> <td>40</td> <td>20</td> <td>60</td> <td>5</td> <td>15</td> <td>15</td> <td>60</td> <td>20</td> </tr> </tbody> </table> <table border="1"> <thead> <tr> <th></th> <th>tCLR</th> <th>tRC</th> <th>tREA</th> <th>tREH</th> <th>tCEA</th> <th>tRP</th> <th>tWHR</th> <th>tRST</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>10</td> <td>50</td> <td>30</td> <td>15</td> <td>45</td> <td>25</td> <td>60</td> <td>5/10/500</td> </tr> <tr> <td>After</td> <td>20</td> <td>60</td> <td>45</td> <td>20</td> <td>55</td> <td>40</td> <td>80</td> <td>20/50/500</td> </tr> </tbody> </table> <p>2) Change ECC Algorithm</p> <p>3) Change NOP - Number of partial program cycle in the same page is changed to 1.</p> <p>4) Change valid block number (min)</p> <table border="1"> <thead> <tr> <th></th> <th>valid block number</th> </tr> </thead> <tbody> <tr> <td>Before</td> <td>2008</td> </tr> <tr> <td>After</td> <td>1968</td> </tr> </tbody> </table>		tWP	tWH	tWC	tALS	tALH	tDH	tR	tAR	Before	25	15	50	0	10	10	50	10	After	40	20	60	5	15	15	60	20		tCLR	tRC	tREA	tREH	tCEA	tRP	tWHR	tRST	Before	10	50	30	15	45	25	60	5/10/500	After	20	60	45	20	55	40	80	20/50/500		valid block number	Before	2008	After	1968	Jan. 18. 2006	Preliminary
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**FEATURES SUMMARY****HIGH DENSITY NAND FLASH MEMORIES**

- Cost effective solutions for mass storage applications

**NAND INTERFACE**

- x8 bus width
- Multiplexed address/ Data
- Pinout compatibility for all densities

**SUPPLY VOLTAGE**

- 3.3V device : VCC = 2.7V to 3.6 V : HY27UT084G2M

**MEMORY CELL ARRAY**

- (2K + 64) bytes x 128 pages x 2048 blocks

**PAGE SIZE**

- x8 device : (2048+64 spare) bytes  
: HY27UT084G2M

**BLOCK SIZE**

- x8 device : (256K+8K) bytes

**PAGE READ / PROGRAM**

- Random access: 60us (Max)
- Sequential access: 60ns (Min)
- Page program time: 800us (Typ)

**FAST BLOCK ERASE**

- Block erase time: 2ms (Typ)

**STATUS REGISTER****ELECTRONIC SIGNATURE**

- 1st cycle: Manufacturer Code
- 2nd cycle: Device Code
- 3rd cycle: Internal chip number, Cell Type, Number of Simultaneously Programmed Pages.
- 4th cycle: Page size, Block size, Organization, Spare size

**CHIP ENABLE DON'T CARE**

- Simple interface with microcontroller

**HARDWARE DATA PROTECTION**

- Program/Erase locked during Power transitions.

**SERIAL NUMBER OPTION****DATA RETENTION**

- 10000 Program / Erase cycles (with 4bit/528byte ECC)
- 10 Years Data Retention

**PACKAGE**

- HY27UT084G2M-T(P)
  - : 48-pin TSOP1(12 x 20 x 1.2 mm)
  - HY27UT084G2M-T (Lead)
  - HY27UT084G2M-TP (Lead Free)

## 1. SUMMARY DESCRIPTION

HY27UT084G2M is a 512Mx8bit with spare 16Mx8bit capacity. The device is offered in 3.3V Vcc Power supply. Its MLC NAND cell provides the most cost-effective solution for the solid state mass storage market.

The memory is divided into blocks that can be erased independently so it is possible to preserve valid data while old data is erased.

The device contains 2048 blocks, composed by 128 pages consisting in two NAND structures of 32 series connected Flash cells. All cell hold two bit. Even pages are stored in the LSB of the cells and odd pages are stored in the MSB of the cells.

A program operation allows to write the 2112-byte page in typical 800us and an erase operation can be performed in typical 2ms on a 256K-byte block.

Data in the page can be read out at 60ns cycle time per byte. The I/O pins serve as the ports for address and data input/output as well as command input. This interface allows a reduced pin count and easy migration towards different densities, without any rearrangement of footprint.

Commands, Data and Addresses are synchronously introduced using  $\overline{CE}$ ,  $\overline{WE}$ , ALE and CLE input pin.

The on-chip Program/Erase Controller automates all program and erase functions including pulse repetition, where required, and internal verification and margining of data.

The modify operations can be locked using the WP input pin.

The output pin R/B (open drain buffer) signals the status of the device during each operation. In a system with multiple memories the R/B pins can be connected all together to provide a global status signal.

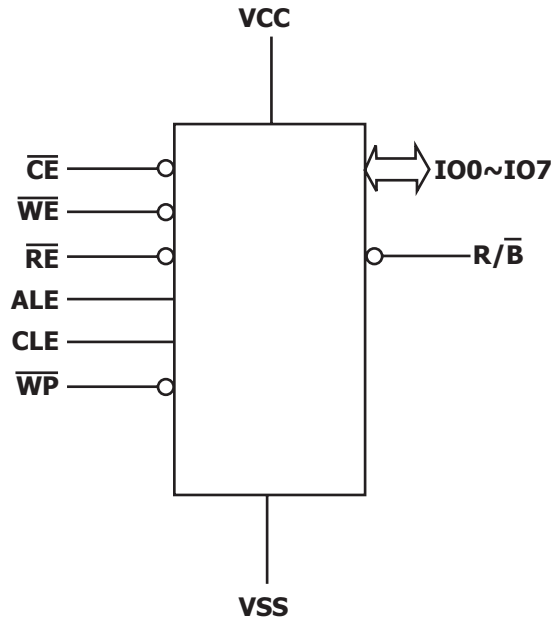
Even the write-intensive systems can take advantage of the HY27UT084G2M's extended reliability of 10K (with 4bit/528 Byte ECC) Program/Erase cycles.

The chip is offered with the CE don't care function. This option allows the direct download of the code from the NAND Flash memory device by a microcontroller, since the  $\overline{CE}$  transitions do not stop the read operation.

The HY27UT084G2M is available in 48 - TSOP1 12 x 20 mm package.

### 1.1 Product List

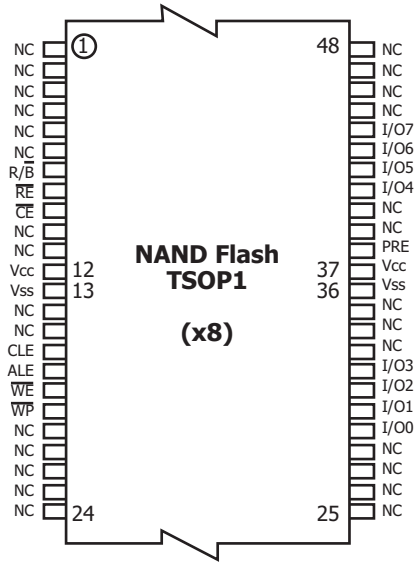
PART NUMBER	ORIZATION	VCC RANGE	PACKAGE
HY27UT084G2M	x8	2.7~3.6 Volt	TSOP48



**Figure1: Logic Diagram**

IO15 - IO8	Data Input / Outputs
IO7 - IO0	Data Input / Outputs
CLE	Command latch enable
ALE	Address latch enable
$\overline{CE}$	Chip Enable
$\overline{RE}$	Read Enable
$\overline{WE}$	Write Enable
$\overline{WP}$	Write Protect
$R/\overline{B}$	Ready / Busy
Vcc	Power Supply
Vss	Ground
NC	No Connection

**Table 1: Signal Names**



**Figure 2. 48TSOP1 Contactions, x8 Device**

**1.2 PIN DESCRIPTION**

Pin Name	Description
IO0-IO7	<b>DATA INPUTS/OUTPUTS</b> The IO pins allow to input command, address and data and to output data during read / program operations. The inputs are latched on the rising edge of Write Enable (WE). The I/O buffer float to High-Z when the device is deselected or the outputs are disabled.
CLE	<b>COMMAND LATCH ENABLE</b> This input activates the latching of the IO inputs inside the Command Register on the Rising edge of Write Enable (WE).
ALE	<b>ADDRESS LATCH ENABLE</b> This input activates the latching of the IO inputs inside the Address Register on the Rising edge of Write Enable (WE).
$\overline{\text{CE}}$	<b>CHIP ENABLE</b> This input controls the selection of the device. When the device is busy $\overline{\text{CE}}$ low does not deselect the memory.
$\overline{\text{WE}}$	<b>WRITE ENABLE</b> This input acts as clock to latch Command, Address and Data. The IO inputs are latched on the rise edge of WE.
$\overline{\text{RE}}$	<b>READ ENABLE</b> The $\overline{\text{RE}}$ input is the serial data-out control, and when active drives the data onto the I/O bus. Data is valid tREA after the falling edge of $\overline{\text{RE}}$ which also increments the internal column address counter by one.
$\overline{\text{WP}}$	<b>WRITE PROTECT</b> The $\overline{\text{WP}}$ pin, when Low, provides an Hardware protection against undesired modify (program / erase) operations.
R/ $\overline{\text{B}}$	<b>READY BUSY</b> The Ready/Busy output is an Open Drain pin that signals the state of the memory.
VCC	<b>SUPPLY VOLTAGE</b> The VCC supplies the power for all the operations (Read, Write, Erase).
VSS	GROUND
NC	NO CONNECTION

**Table 2: Pin Description**

**NOTE:**

1. A 0.1uF capacitor should be connected between the VCC Supply Voltage pin and the VSS Ground pin to decouple the current surges from the power supply. The PCB track widths must be sufficient to carry the currents required during program and erase operations.



	<b>I00</b>	<b>I01</b>	<b>I02</b>	<b>I03</b>	<b>I04</b>	<b>I05</b>	<b>I06</b>	<b>I07</b>
<b>1st Cycle</b>	A0	A1	A2	A3	A4	A5	A6	A7
<b>2nd Cycle</b>	A8	A9	A10	A11	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>
<b>3rd Cycle</b>	A12	A13	A14	A15	A16	A17	A18	A19
<b>4th Cycle</b>	A20	A21	A22	A23	A24	A25	A26	A27
<b>5th Cycle</b>	A28	A29	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>	L <sup>(1)</sup>

**Table 3: Address Cycle Map(x8)**

**NOTE:**

1. L must be set to Low.

<b>FUNCTION</b>	<b>1st CYCLE</b>	<b>2nd CYCLE</b>	<b>3rd CYCLE</b>	<b>Acceptable command during busy</b>
<b>READ 1</b>	00h	30h	-	
<b>READ ID</b>	90h	-	-	
<b>RESET</b>	FFh	-	-	Yes
<b>PAGE PROGRAM (start)</b>	80h	10h	-	
<b>BLOCK ERASE</b>	60h	D0h	-	
<b>READ STATUS REGISTER</b>	70h	-	-	Yes
<b>RANDOM DATA INPUT</b>	85h	-	-	
<b>RANDOM DATA OUTPUT</b>	05h	E0h	-	

**Table 4: Command Set**

CLE	ALE	$\overline{CE}$	$\overline{WE}$	$\overline{RE}$	$\overline{WP}$	MODE	
H	L	L	Rising	H	X	Read Mode	Command Input
L	H	L	Rising	H	X		Address Input(5 cycles)
H	L	L	Rising	H	H	Write Mode	Command Input
L	H	L	Rising	H	H		Address Input(5 cycles)
L	L	L	Rising	H	H	Data Input	
L	L	L <sup>(1)</sup>	H	Falling	X	Sequential Read and Data Output	
L	L	L	H	H	X	During Read (Busy)	
X	X	X	X	X	H	During Program (Busy)	
X	X	X	X	X	H	During Erase (Busy)	
X	X	X	X	X	L	Write Protect	
X	X	H	X	X	0V/Vcc	Stand By	

**Table 5: Mode Selection**

**NOTE:**

1. With the  $\overline{CE}$  don't care option  $\overline{CE}$  high during latency time does not stop the read operation

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## **2. BUS OPERATION**

There are six standard bus operations that control the device. These are Command Input, Address Input, Data Input, Data Output, Write Protect, and Standby.

Typically glitches less than 5 ns on Chip Enable, Write Enable and Read Enable are ignored by the memory and do not affect bus operations.

### **2.1 Command Input.**

Command Input bus operation is used to give a command to the memory device. Commands are accepted with Chip Enable low, Command Latch Enable High, Address Latch Enable low and Read Enable High and latched on the rising edge of Write Enable. Moreover for commands that start a modify operation (write/erase) the Write Protect pin must be high. See figure 4 and table 14 for details of the timings requirements. Command codes are always applied on IO7:0, disregarding the bus configuration (X8).

### **2.2 Address Input.**

Address Input bus operation allows the insertion of the memory address. To insert the 30 addresses is needed to access the 4Gbit, 5 clock cycles are needed. Addresses are accepted with Chip Enable low, Address Latch Enable High, Command Latch Enable low and Read Enable High and latched on the rising edge of Write Enable. Moreover for commands that start a modify operation (write/erase) the Write Protect pin must be high. See figure 5 and table 15 for details of the timings requirements. Addresses are always applied on IO7:0, disregarding the bus configuration (X8).

### **2.3 Data Input.**

Data Input bus operation allows to feed to the device the data to be programmed. The data insertion is serially and timed by the Write Enable cycles. Data are accepted only with Chip Enable low, Address Latch Enable low, Command Latch Enable low, Read Enable High, and Write Protect High and latched on the rising edge of Write Enable. See figure 6 and table 14 for details of the timings requirements.

### **2.4 Data Output.**

Data Output bus operation allows to read data from the memory array and to check the status register content, the ID data. Data can be serially shifted out toggling the Read Enable pin with Chip Enable low, Write Enable High, Address Latch Enable low, and Command Latch Enable low. See figures 7,9,10 and table 14 for details of the timings requirements.

### **2.5 Write Protect.**

Hardware Write Protection is activated when the Write Protect pin is low. In this condition modify operation do not start and the content of the memory is not altered. Write Protect pin is not latched by Write Enable to ensure the protection even during the power up.

### **2.6 Standby.**

In Standby the device is deselected, outputs are disabled and Power Consumption reduced.

### 3. DEVICE OPERATION

#### 3.1 Page Read.

Upon initial device power up, the device defaults to Read mode. This operation is also initiated by writing 00h and 30h to the command register along with five address cycles. In two consecutive read operations, the second one doesn't need 00h command, which five address cycles and 30h command initiates that operation. Two types of operations are available: random read, serial page read. The random read mode is enabled when the page address is changed. The 2112 bytes (X8 device) of data within the selected page are transferred to the data registers in less than 60us(tR). The system controller may detect the completion of this data transfer 60us(tR) by analyzing the output of R/B pin. Once the data in a page is loaded into the data registers, they may be read out in 60ns cycle time by sequentially pulsing  $\overline{RE}$ . The repetitive high to low transitions of the  $\overline{RE}$  clock make the device output the data starting from the selected column address up to the last column address.

The device may output random data in a page instead of the consecutive sequential data by writing random data output command.

The column address of next data, which is going to be out, may be changed to the address which follows random data output command.

Random data output can be operated multiple times regardless of how many times it is done in a page.

#### 3.2 Page Program.

The device is programmed by page. The number of consecutive partial page programming operation within the same page without an intervening erase operation must not exceed 1 time.

The addressing should be done in sequential order in a block. A page program cycle consists of a serial data loading period in which up to 2112bytes (X8 device) of data may be loaded into the data register, followed by a non-volatile programming period where the loaded data is programmed into the appropriate cell.

The serial data loading period begins by inputting the Serial Data Input command (80h), followed by the five cycle address inputs and then serial data. The words other than those to be programmed do not need to be loaded. The device supports random data input in a page. The column address of next data, which will be entered, may be changed to the address which follows random data input command (85h). Random data input may be operated multiple times regardless of how many times it is done in a page.

The Page Program confirm command (10h) initiates the programming process. Writing 10h alone without previously entering the serial data will not initiate the programming process.

The internal write state controller automatically executes the algorithms and timings necessary for program and verify, thereby freeing the system controller for other tasks. Once the program process starts, the Read Status Register command may be entered to read the status register.

The system controller can detect the completion of a program cycle by monitoring the  $\overline{R/B}$  output, or the Status bit (I/O 6) of the Status Register. Only the Read Status command and Reset command are valid while programming is in progress. When the Page Program is complete, the Write Status Bit (I/O 0) may be checked.

The internal write verify detects only errors for "1"s that are not successfully programmed to "0"s.

The command register remains in Read Status command mode until another valid command is written to the command register. Figure 12 details the sequence.

### 3.3 Block Erase.

The Erase operation is done on a block basis. Block address loading is accomplished in two cycles initiated by an Erase Setup command (60h). Only address A19 to A29 (X8) is valid while A12 to A18 (X8) is ignored. The Erase Confirm command (D0h) following the block address loading initiates the internal erasing process. This two-step sequence of setup followed by execution command ensures that memory contents are not accidentally erased due to external noise conditions.

At the rising edge of  $\overline{WE}$  after the erase confirm command input, the internal write controller handles erase and erase-verify.

Once the erase process starts, the Read Status Register command may be entered to read the status register. The system controller can detect the completion of an erase by monitoring the  $R/\overline{B}$  output, or the Status bit (I/O 6) of the Status Register. Only the Read Status command and Reset command are valid while erasing is in progress. When the erase operation is completed, the Write Status Bit (I/O 0) may be checked.

Figure 14 details the sequence.

### 3.4 Read Status Register.

The device contains a Status Register which may be read to find out whether read, program or erase operation is completed, and whether the program or erase operation is completed successfully. After writing 70h command to the command register, a read cycle outputs the content of the Status Register to the I/O pins on the falling edge of  $\overline{CE}$  or  $\overline{RE}$ , whichever occurs last. This two line control allows the system to poll the progress of each device in multiple memory connections even when  $R/\overline{B}$  pins are common-wired.  $\overline{RE}$  or  $\overline{CE}$  does not need to be toggled for updated status. Refer to table 15 for specific Status Register definitions. The command register remains in Status Read mode until further commands are issued to it. Therefore, if the status register is read during a random read cycle, the read command (00h) should be given before starting read cycles.

### 3.5 Read ID.

The device contains a product identification mode, initiated by writing 90h to the command register, followed by an address input of 00h. Four read cycles sequentially output the manufacturer code (ADh), and the device code and 3rd cycle ID, 4th cycle ID respectively. The command register remains in Read ID mode until further commands are issued to it. Figure 15 shows the operation sequence, while tables 17 explain the byte meaning.

### 3.6 Reset.

The device offers a reset feature, executed by writing FFh to the command register. When the device is in Busy state during random read, program or erase mode, the reset operation will abort these operations. The contents of memory cells being altered are no longer valid, as the data will be partially programmed or erased. The command register is cleared to wait for the next command, and the Status Register is cleared to value E0h when  $\overline{WP}$  is high. Refer to table 15 for device status after reset operation. If the device is already in reset state a new reset command will not be accepted by the command register. The  $R/\overline{B}$  pin goes low for  $t_{RST}$  after the Reset command is written. Refer to Figure 18.

## 4. OTHER FEATURES

### 4.1 Data Protection & Power On/Off Sequence

The device is designed to offer protection from any involuntary program/erase during power-transitions. An internal voltage detector disables all functions whenever  $V_{cc}$  is below about 2V(3.3V device).  $\overline{WP}$  pin provides hardware protection and is recommended to be kept at VIL during power-up and power-down. A recovery time of minimum 10us is required before internal circuit gets ready for any command sequences as shown in Figure 19. The two-step command sequence for program/erase provides additional software protection.

If the power is dropped during the ready read/write/erase operation, Power protection function may not guaranteed the data. Power protection function is only available during the power on/off sequence.

### 4.2 Ready/Busy.

The device has a Ready/Busy output that provides method of indicating the completion of a page program, erase, random read completion. The  $R/\overline{B}$  pin is normally high and goes to low when the device is busy (after a reset, read, program, erase operation). It returns to high when the internal controller has finished the operation. The pin is an open-drain driver thereby allowing two or more  $R/\overline{B}$  outputs to be Or-tied. Because pull-up resistor value is related to  $t_r(R/\overline{B})$  and current drain during busy ( $I_{busy}$ ), an appropriate value can be obtained with the following reference chart (Fig 20). Its value can be determined by the following guidance.

Parameter	Symbol	Min	Typ	Max	Unit
Valid Block Number	NVB	1989		2048	Blocks

**Table 6: Valid Blocks Number**

**NOTE:**

1. The 1st block is guaranteed to be a valid block at the time of shipment.

Symbol	Parameter		Value	Unit
TA	Ambient Operating Temperature (Temperature Range Option 1)		0 to 70	°C
	Ambient Operating Temperature (Temperature Range Option 2)		-25 to 85	°C
	Ambient Operating Temperature (Temperature Range Option 3)		-40 to 85	°C
TBIAS	Temperature Under Bias		-50 to 125	°C
TSTG	Storage Temperature		-65 to 150	°C
V <sub>IO</sub> <sup>(2)</sup>	Input or Output Voltage	3.3V Device	-0.6 to 4.6	V
V <sub>CC</sub>	Supply Voltage		-0.6 to 4.6	V

**Table 7: Absolute maximum ratings**

**NOTE:**

1. Except for the rating "Operating Temperature Range", stresses above those listed in the Table "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the Hynix SURE Program and other relevant quality documents.
2. Minimum Voltage may undershoot to -2V during transition and for less than 20ns during transitions.

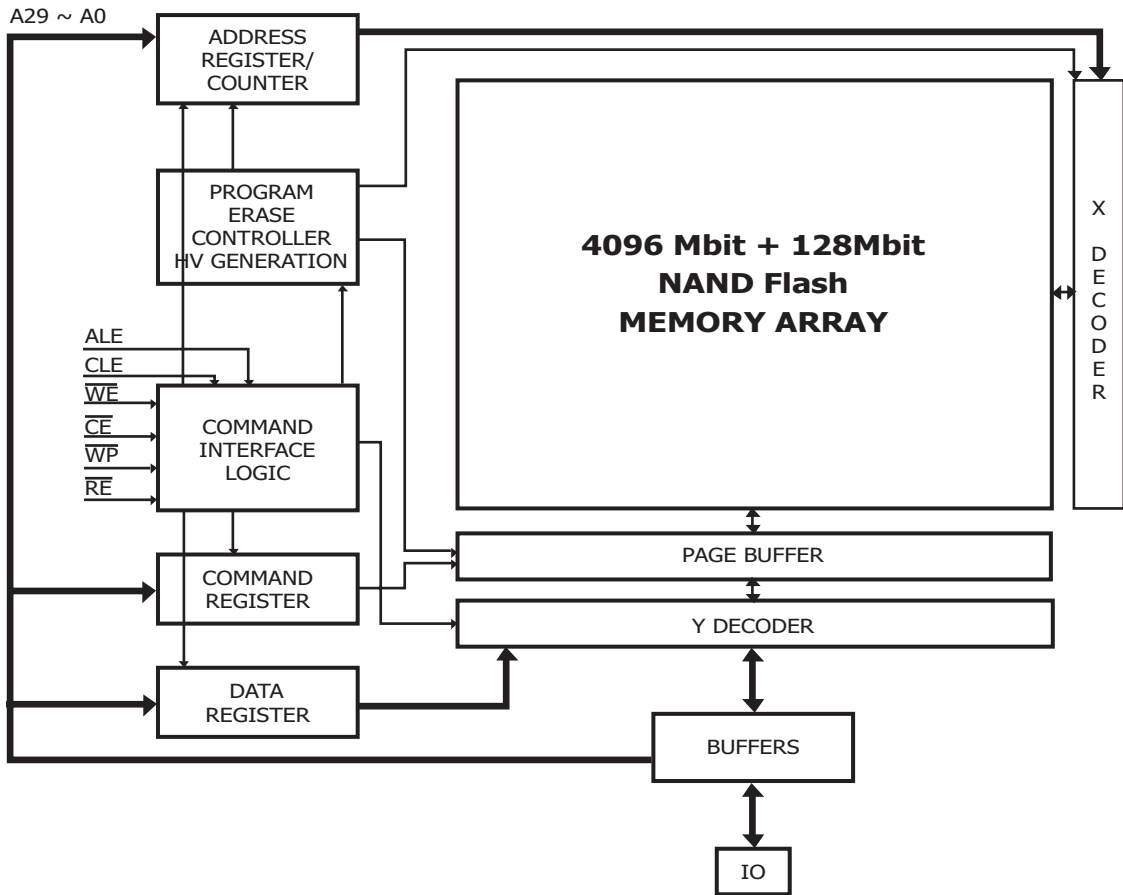


Figure 3: Block Diagram



Parameter		Symbol	Test Conditions	3.3Volt			Unit
				Min	Typ	Max	
Operating Current	Sequential Read	I <sub>CC1</sub>	$\overline{trc}=60\text{ns}$ $\overline{CE}=V_{IL}, I_{OUT}=0\text{mA}$	-	15	30	mA
	Program	I <sub>CC2</sub>	-	-	15	30	mA
	Erase	I <sub>CC3</sub>	-	-	15	30	mA
Stand-by Current (TTL)		I <sub>CC4</sub>	$\overline{CE}=V_{IH}$ , $\overline{WP}=0\text{V}, V_{CC}$	-		1	mA
Stand-by Current (CMOS)		I <sub>CC5</sub>	$\overline{CE}=V_{CC}-0.2$ , $\overline{WP}=0\text{V}, V_{CC}$	-	10	50	uA
Input Leakage Current		I <sub>LI</sub>	V <sub>IN</sub> =0 to V <sub>CC</sub> (max)	-	-	± 10	uA
Output Leakage Current		I <sub>LO</sub>	V <sub>OUT</sub> =0 to V <sub>CC</sub> (max)	-	-	± 10	uA
Input High Voltage		V <sub>IH</sub>	-	0.8xV <sub>CC</sub>	-	V <sub>CC</sub> +0.3	V
Input Low Voltage		V <sub>IL</sub>	-	-0.3	-	0.2xV <sub>CC</sub>	V
Output High Voltage Level		V <sub>OH</sub>	I <sub>OH</sub> =-400uA	2.4	-	-	V
Output Low Voltage Level		V <sub>OL</sub>	I <sub>OL</sub> =2.1mA	-	-	0.4	V
Output Low Current (R/B)		$\frac{I_{OL}}{(R/\overline{B})}$	V <sub>OL</sub> =0.6V	8	10	-	mA

**Table 8: DC and Operating Characteristics**

Parameter	Value
	3.3Volt
Input Pulse Levels	0.4V to 2.4V
Input Rise and Fall Times	5ns
Input and Output Timing Levels	1.5V
Output Load (2.7V - 3.3V)	1 TTL GATE and CL=50pF
Output Load (3.0V - 3.6V)	1 TTL GATE and CL=100pF

**Table 9: AC Conditions**

Item	Symbol	Test Condition	Min	Max	Unit
Input / Output Capacitance	C <sub>I/O</sub>	V <sub>IL</sub> =0V	-	10	pF
Input Capacitance	C <sub>IN</sub>	V <sub>IN</sub> =0V	-	10	pF

**Table 10: Pin Capacitance (TA=25C, F=1.0MHz)**

Parameter	Symbol	Min	Typ	Max	Unit
Program Time	t <sub>PROG</sub>	-	800	2000	us
Number of partial Program Cycles in the same page	NOP	-	-	1	Cycles
Block Erase Time	t <sub>BERS</sub>	-	2	3	ms

**Table 11: Program / Erase Characteristics**

Parameter	Symbol	3.3Volt		Unit
		Min	Max	
CLE Setup time	tCLS	0		ns
CLE Hold time	tCLH	10		ns
$\overline{\text{CE}}$ setup time	tCS	0		ns
$\overline{\text{CE}}$ hold time	tCH	10		ns
$\overline{\text{WE}}$ pulse width	tWP	40		ns
ALE setup time	tALS	5		ns
ALE hold time	tALH	15		ns
Data setup time	tDS	20		ns
Data hold time	tDH	15		ns
Write Cycle time	tWC	60		ns
$\overline{\text{WE}}$ High hold time	tWH	20		ns
Data Transfer from Cell to register	tr		60	us
ALE to $\overline{\text{RE}}$ Delay	tAR	20		ns
CLE to $\overline{\text{RE}}$ Delay	tCLR	20		ns
Ready to $\overline{\text{RE}}$ Low	tRR	20		ns
$\overline{\text{RE}}$ Pulse Width	tRP	40		ns
$\overline{\text{WE}}$ High to Busy	tWB		100	ns
Read Cycle Time	tRC	60		ns
$\overline{\text{RE}}$ Access Time	tREA		45	ns
$\overline{\text{RE}}$ High to Output High Z	tRHZ		30	ns
$\overline{\text{CE}}$ High to Output High Z	tCHZ		20	ns
$\overline{\text{RE}}$ or $\overline{\text{CE}}$ High to Output Hold	tOH	10		ns
$\overline{\text{RE}}$ High Hold Time	tREH	20		ns
Output High Z to $\overline{\text{RE}}$ low	tIR	0		ns
$\overline{\text{CE}}$ Access Time	tCEA		55	ns
$\overline{\text{WE}}$ High to $\overline{\text{RE}}$ low	tWHR	80		ns
Device Resetting Time (Read / Program / Erase)	tRST		20/50/500 <sup>(1)</sup>	us
Write Protection time	tWW <sup>(2)</sup>	100		ns

**Table 12: AC Timing Characteristics**
**NOTE:**

1. If Reset Command (FFh) is written at Ready state, the device goes into Busy for maximum 5us
2. Program / Erase Enable Operation :  $\overline{\text{WP}}$  high to  $\overline{\text{WE}}$  High.  
Program / Erase Disable Operation :  $\overline{\text{WP}}$  Low to  $\overline{\text{WE}}$  High.

IO	Page Program	Block Erase	Read	CODING
0	Pass / Fail	Pass / Fail	NA	Pass: '0' Fail: '1'
1	NA	NA	NA	-
2	NA	NA	NA	-
3	NA	NA	NA	-
4	NA	NA	NA	-
5	Ready/Busy	Ready/Busy	Ready/Busy	Active: '0' Idle: '1'
6	Ready/Busy	Ready/Busy	Ready/Busy	Busy: '0' Ready: '1'
7	Write Protect	Write Protect	Write Protect	Protected: '0' Not Protected: '1'

**Table 13: Status Register Coding**

DEVICE IDENTIFIER CYCLE	DESCRIPTION
1st	Manufacturer Code
2nd	Device Identifier
3rd	Internal chip number, cell Type, Number of Simultaneously Programmed pages.
4th	Page Size, Block Size, Spare Size, Organization

**Table 14: Device Identifier Coding**

Part Number	Voltage	Bus Width	1st cycle (Manufacture Code)	2nd cycle (Device Code)	3rd cycle	4th cycle
HY27UT084G2M	3.3V	x8	ADh	DCh	84h	25h

**Table 15: Read ID Data Table**

	Description	I07	I06	I05 I04	I03 I02	I01 I00
Die / Package	1					0 0
	2					0 1
	4					1 0
	Reserved					1 1
String Type	Single Level				0 0	
	2x Multi-level				0 1	
	Reserved				1 0	
	Reserved				1 1	
Number of Simultaneously Programmed Pages	1			0 0		
	2			0 1		
	3			1 0		
	4			1 1		
Interleave Program Between multiple chips	Not Support		0			
	Support		1			
Write Cache	Not Support	0				
	Support	1				

**Table 16: 3rd Byte of Device Identifier Description**

	Description	I07	I06	I05-4	I03	I02	I01-0
Page Size (Without Spare Area)	1K						0 0
	2K						0 1
	Reserved						1 0
	Reserved						1 1
Spare Area Size (Byte / 512Byte)	8					0	
	16					1	
Serial Access Time	50ns / 30ns	0			0		
	25ns	0			1		
	Reserved	1			0		
	Reserved	1			1		
Block Size (Without Spare Area)	64K			0 0			
	128K			0 1			
	256K			1 0			
	Reserved			1 1			
Organization	X8		0				
	X16		1				

**Table 17: 4th Byte of Device Identifier Description**

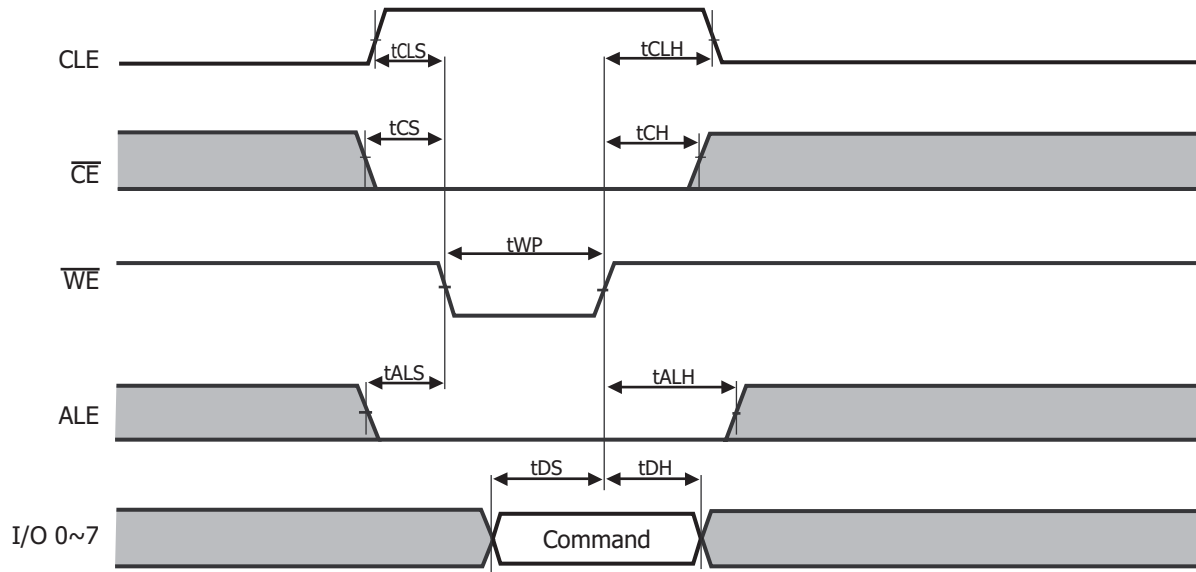
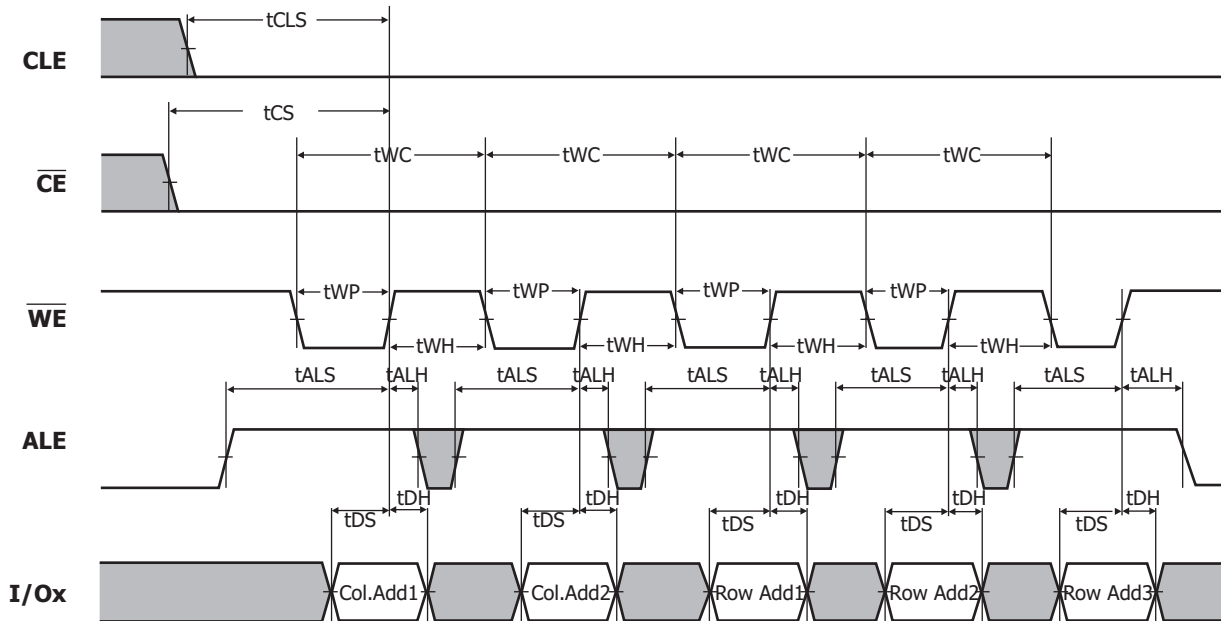
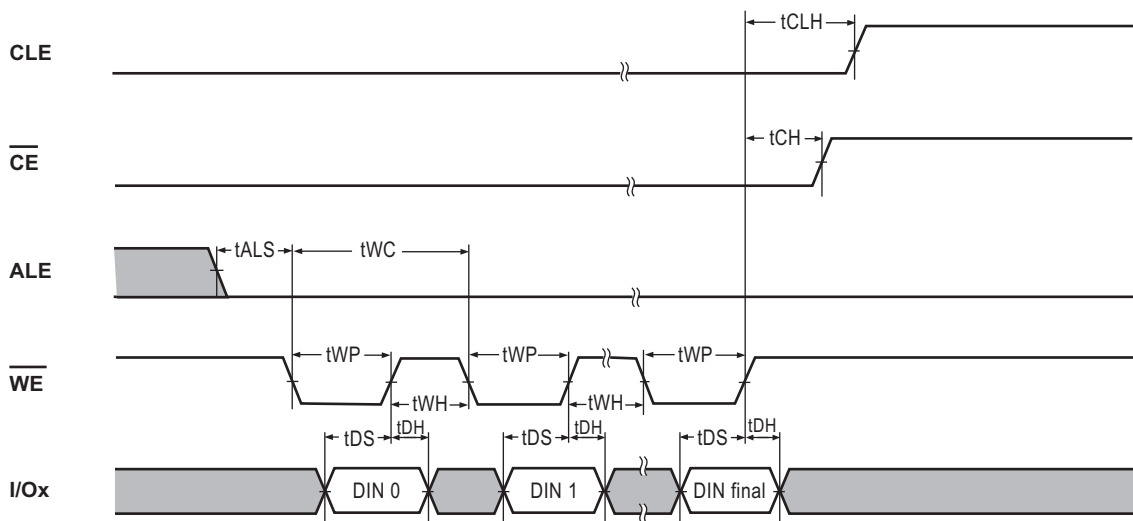


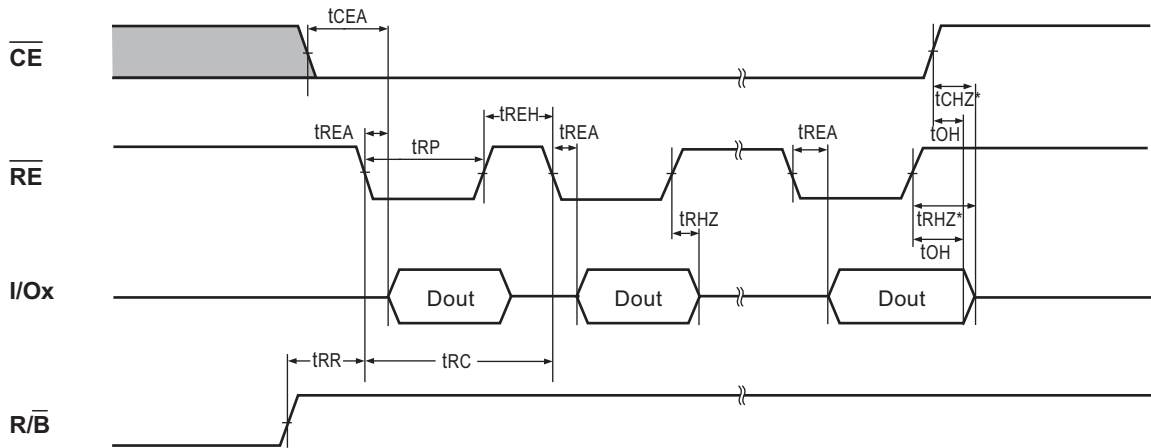
Figure 4: Command Latch Cycle



**Figure 5: Address Latch Cycle**

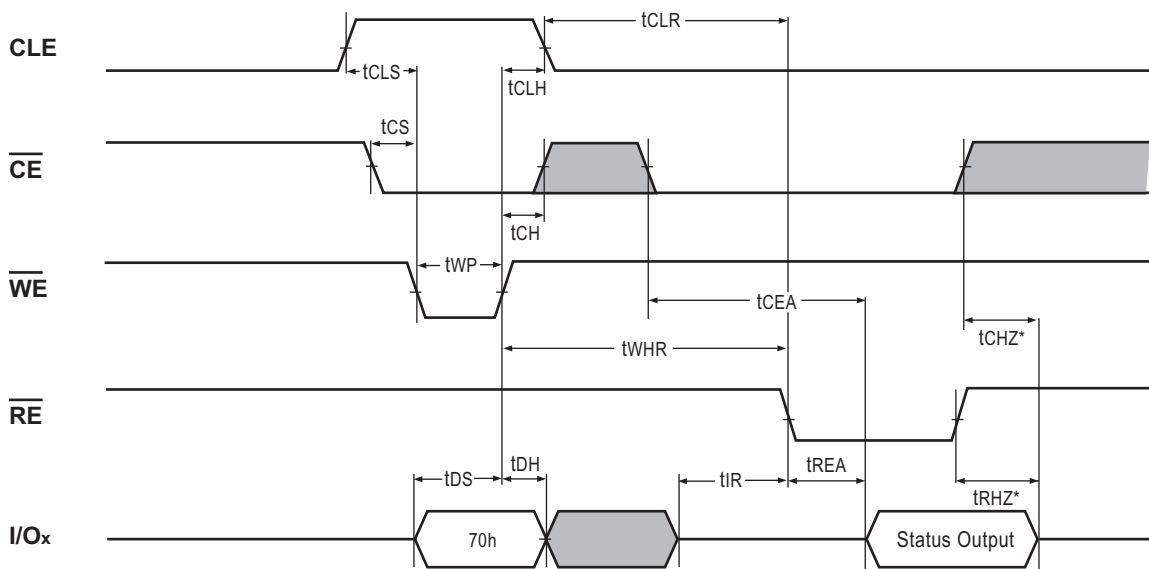


**Figure 6: Input Data Latch Cycle**



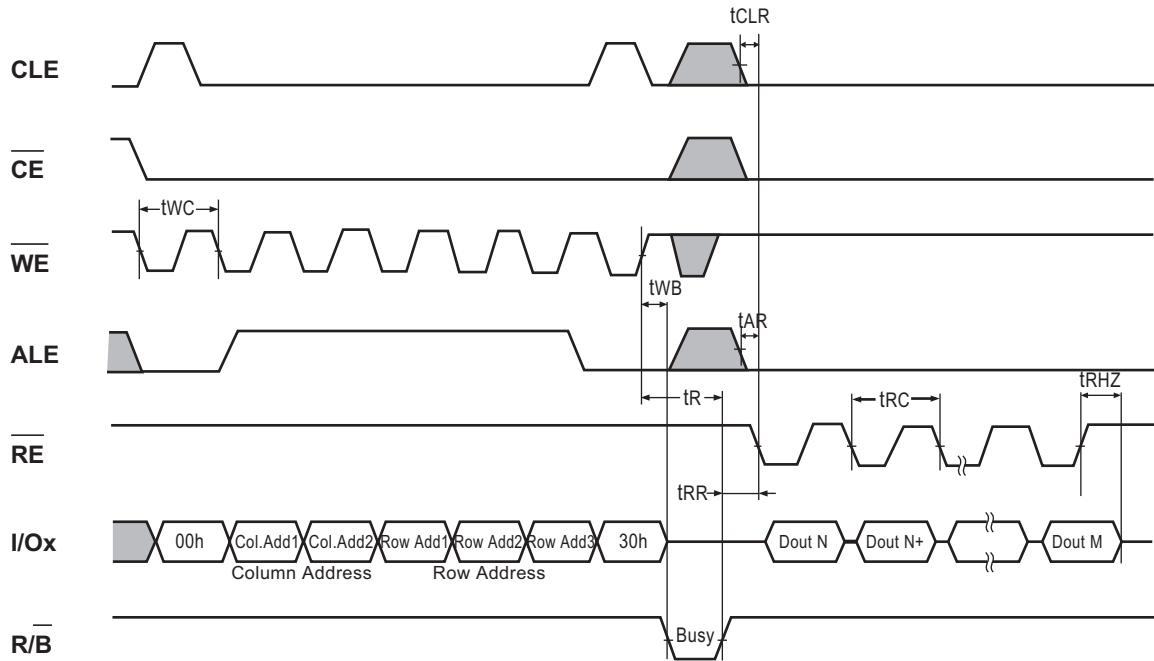
NOTES : Transition is measured  $\pm 200\text{mV}$  from steady state voltage with load.  
This parameter is sampled and not 100% tested.

**Figure 7: Sequential Out Cycle after Read (CLE=L, WE=H, ALE=L)**

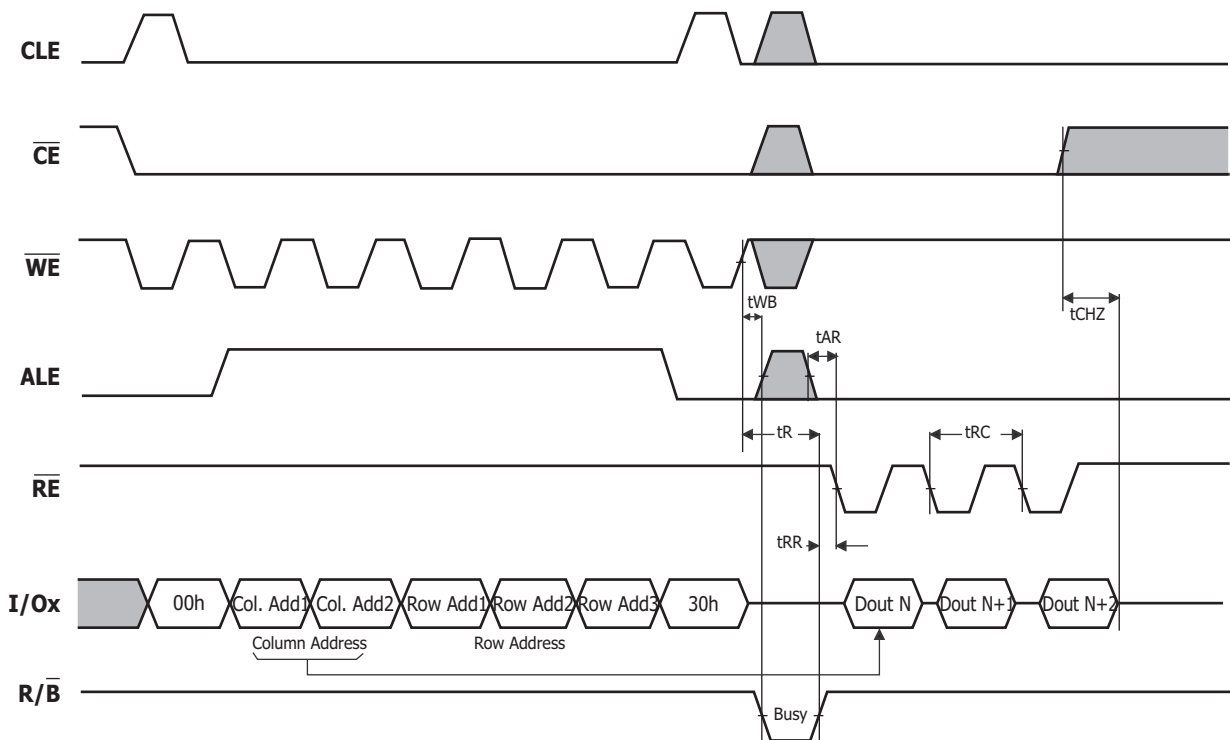


**Figure 8: Status Read Cycle**





**Figure 9: Read1 Operation (Read One Page)**



**Figure 10: Read1 Operation intercepted by CE**

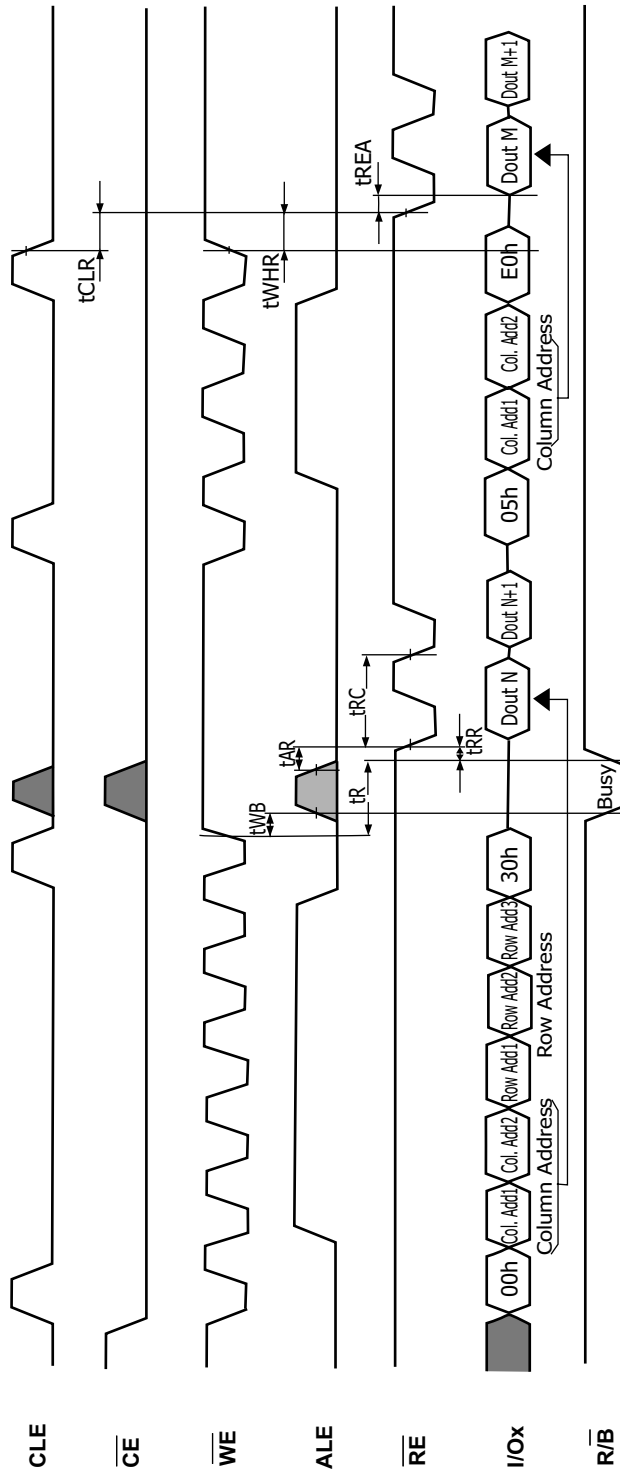
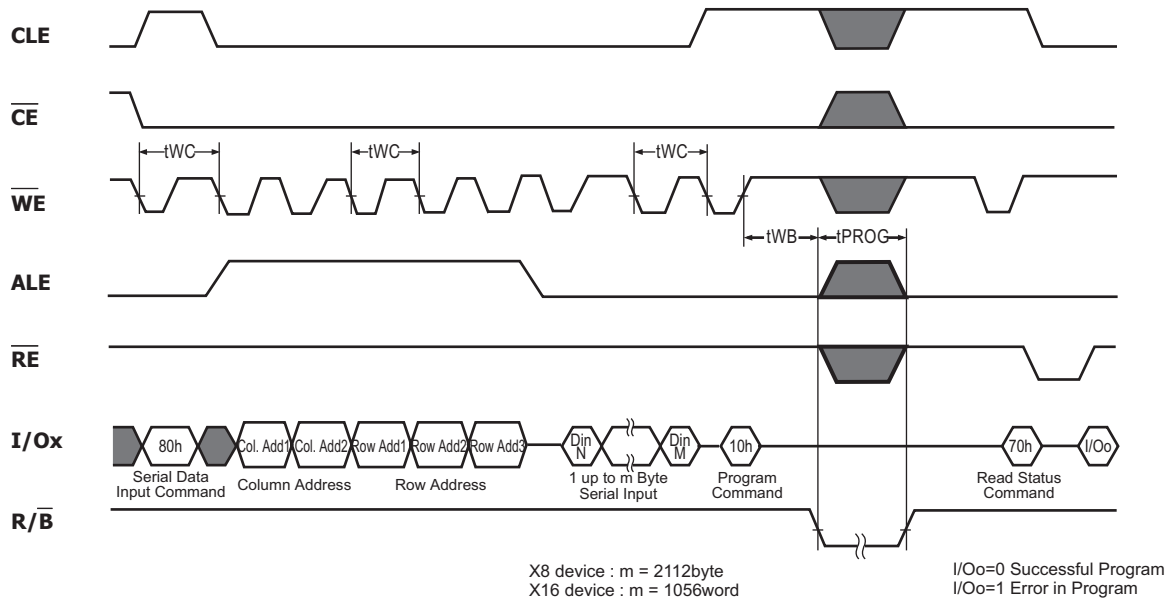
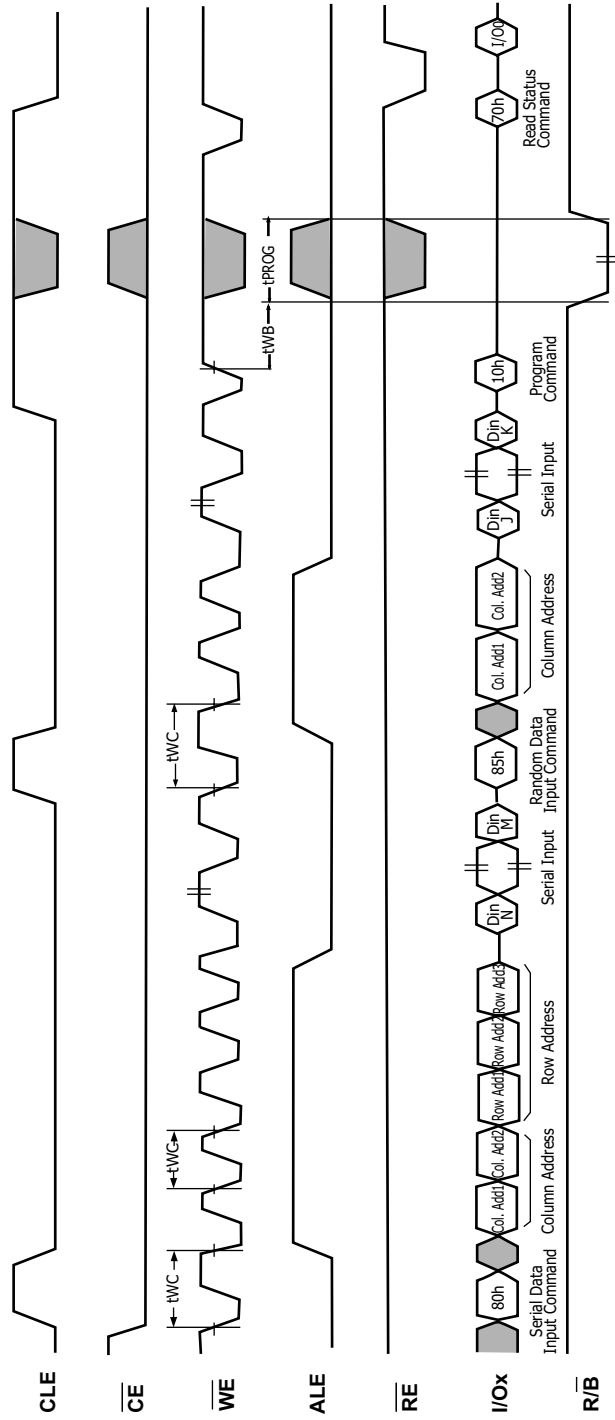


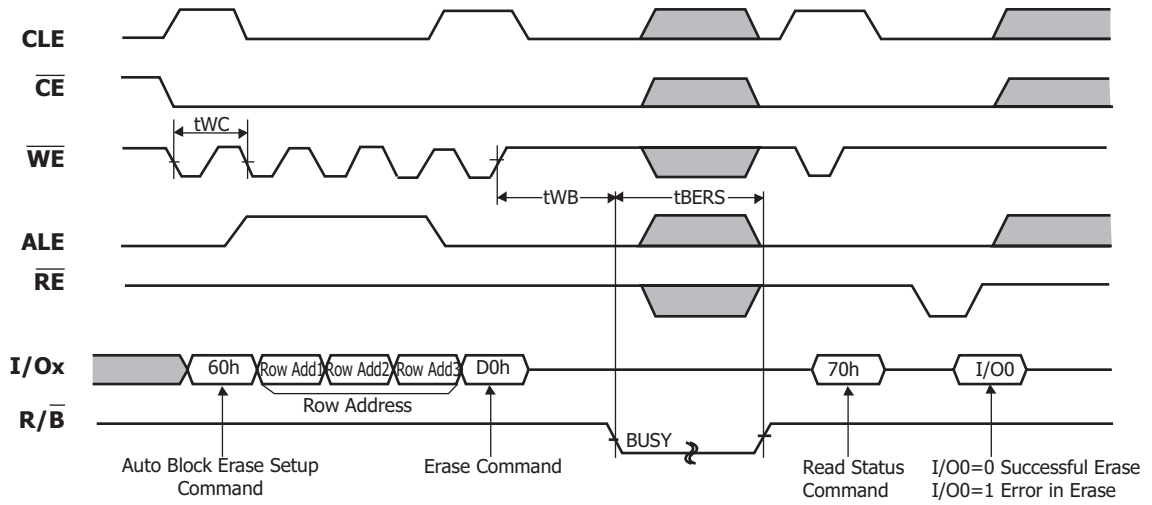
Figure 11 : Random Data output



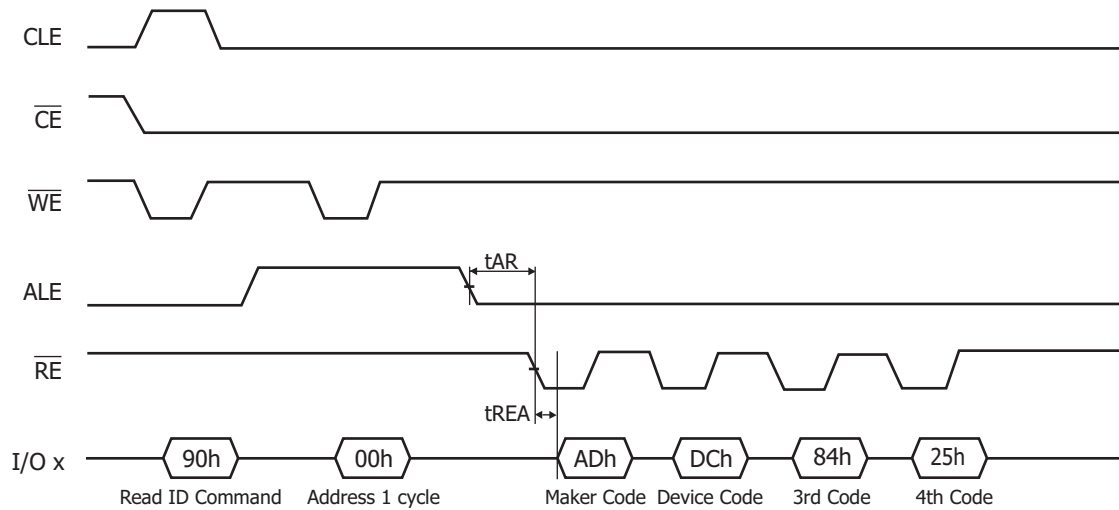
**Figure 12: Page Program Operation**



**Figure 13 : Random Data In**



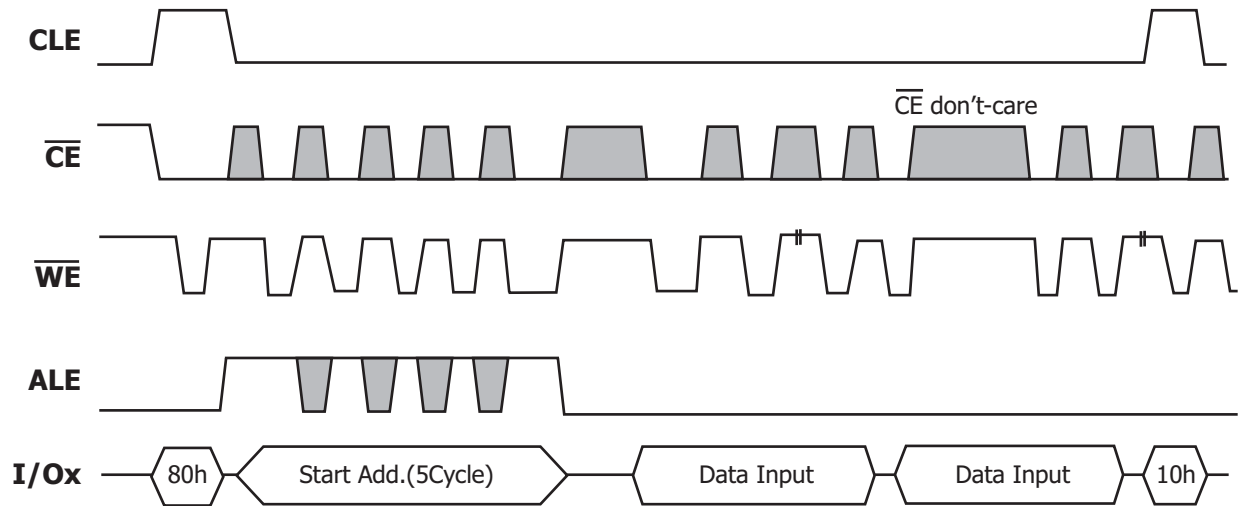
**Figure 14: Block Erase Operation (Erase One Block)**



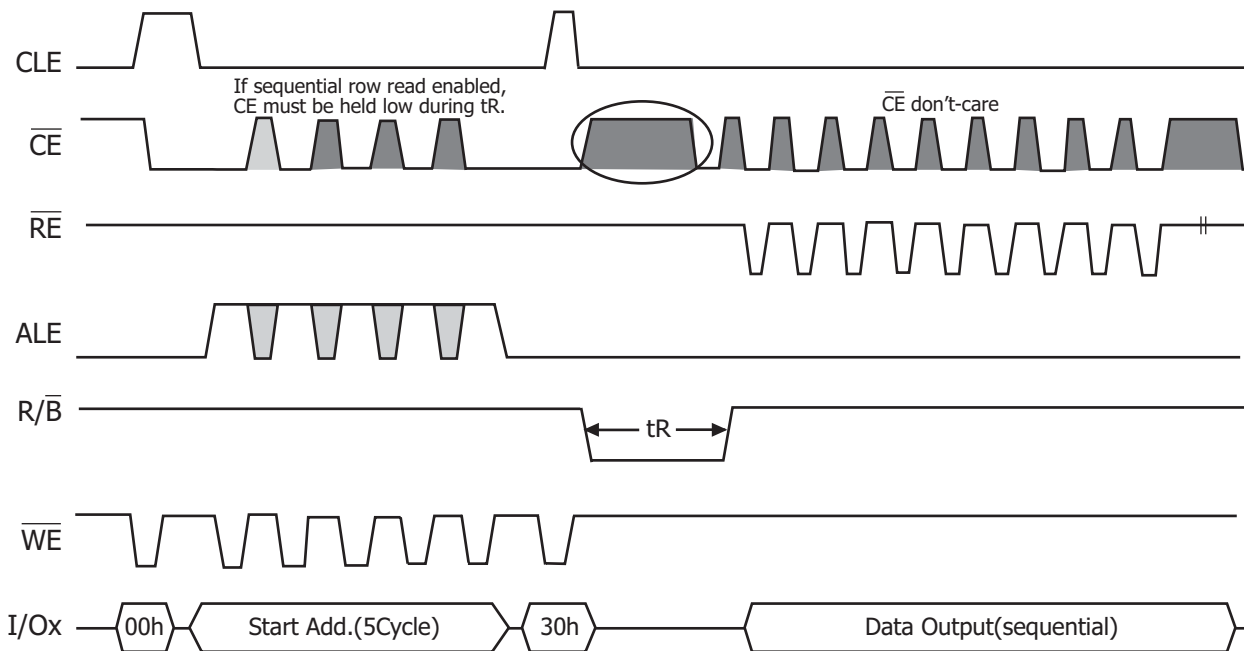
**Figure 15: Read ID Operation**

**System Interface Using  $\overline{CE}$  don't care**

To simplify system interface,  $\overline{CE}$  may be deasserted during data loading or sequential data-reading as shown below. So, it is possible to connect NAND Flash to a microprocessor. The only function that was removed from standard NAND Flash to make  $\overline{CE}$  don't care read operation was disabling of the automatic sequential read function.



**Figure 16: Program Operation with  $\overline{CE}$  don't-care.**



**Figure 17: Read Operation with  $\overline{CE}$  don't-care.**

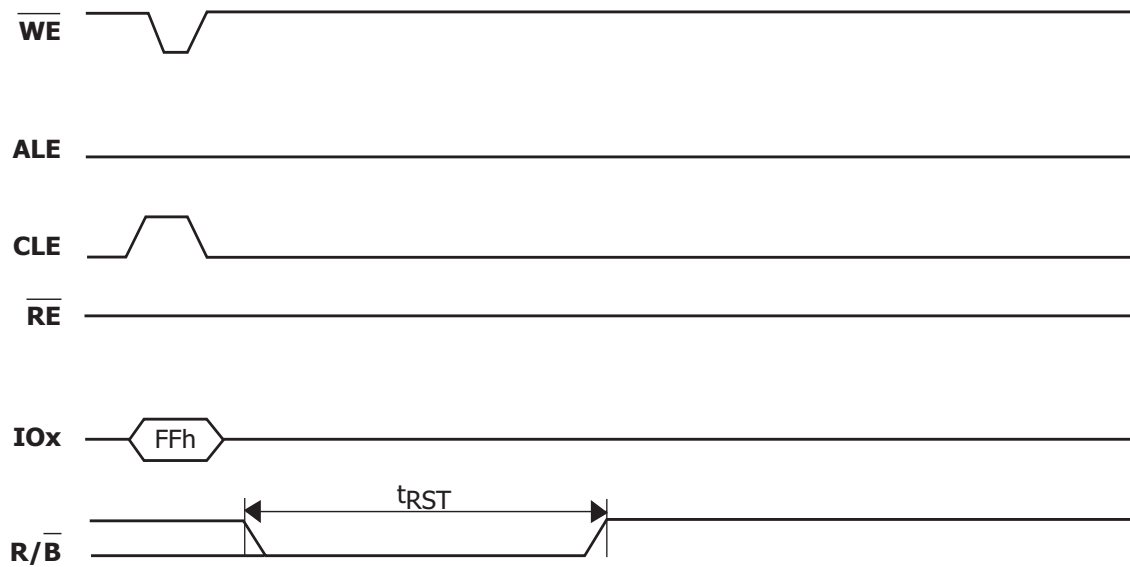
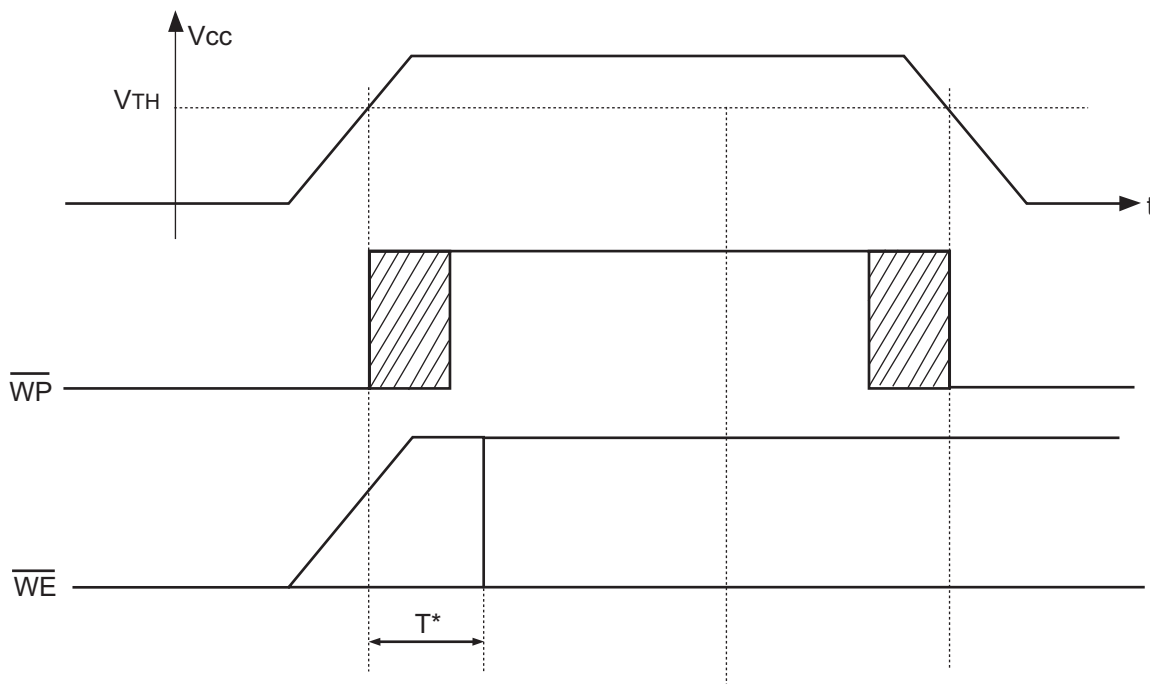


Figure 18: Reset Operation



**Figure 19: Power On and Data Protection Timing**

**VTH = 2.5 Volt for 3.3 Volt Supply devices**



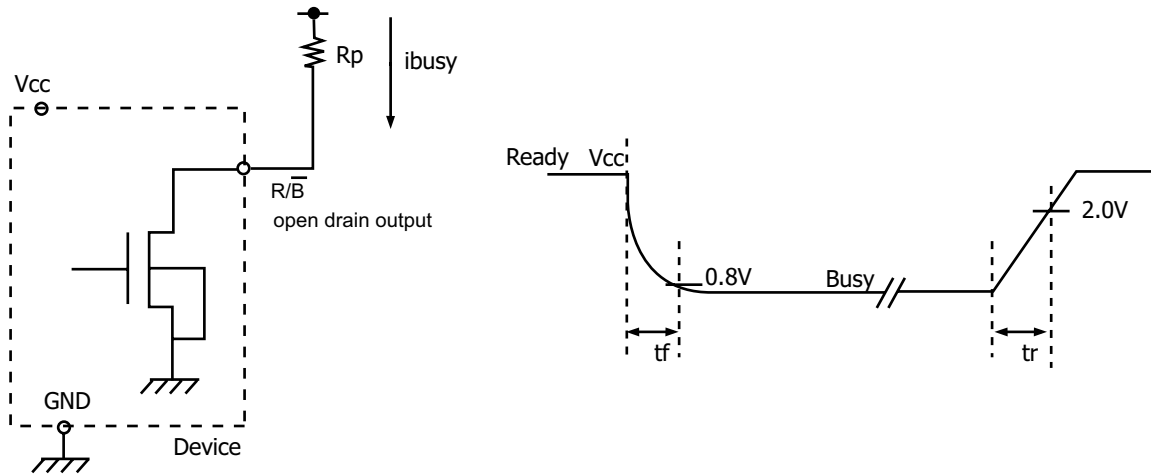
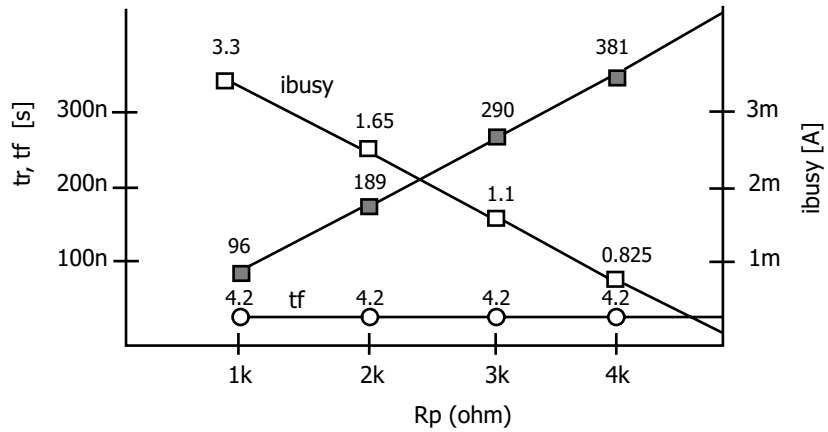


Fig. Rp vs tr, tf & Rp vs ibusy

@ Vcc = 3.3V, Ta = 25°C, CL=100pF



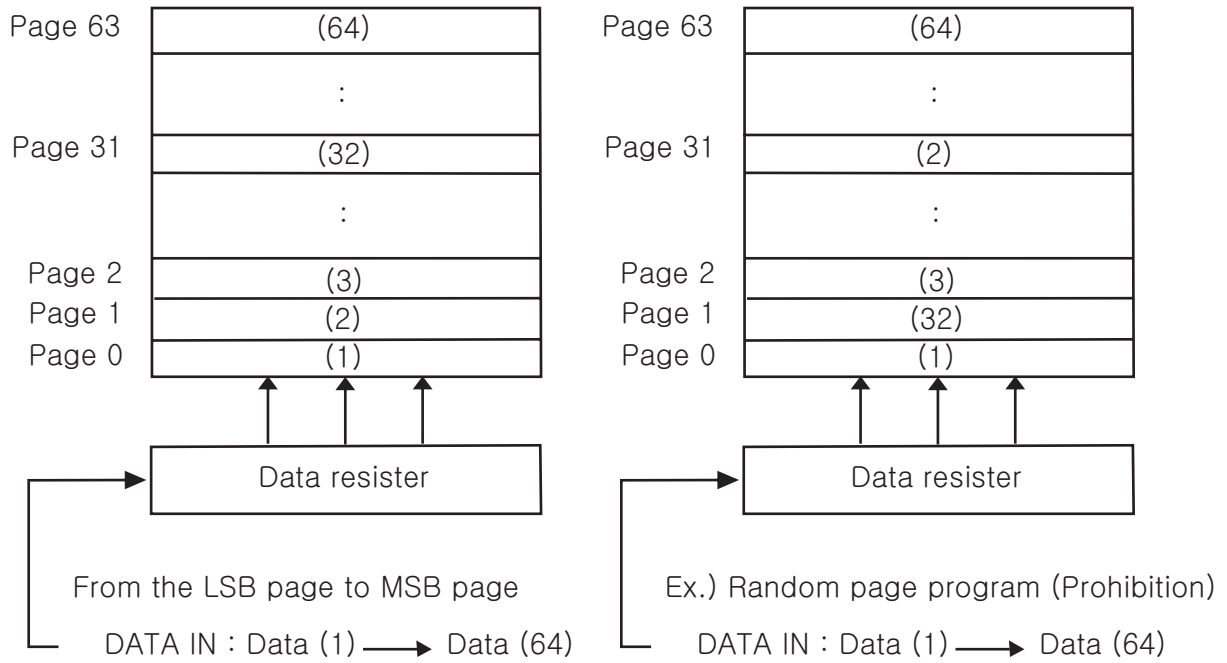
Rp value guidance

$$R_p(\min) = \frac{V_{cc}(\text{Max.}) - V_{OL}(\text{Max.})}{I_{OL} + \sum I_L} = \frac{3.2V}{8mA + \sum I_L}$$

where IL is the sum of the input currents of all devices tied to the R/B pin.

Rp(max) is determined by maximum permissible limit of tr

Figure 20: Ready/Busy Pin electrical specifications



**Figure 21: page programming within a block**

**Bad Block Management**

Devices with Bad Blocks have the same quality level and the same AC and DC characteristics as devices where all the blocks are valid. A Bad Block does not affect the performance of valid blocks because it is isolated from the bit line and common source line by a select transistor. The devices are supplied with all the locations inside valid blocks erased(FFh). The Bad Block Information is written prior to shipping. Any block where the 1st Byte in the spare area of the Last or (Last-2)th page (if the last page is Bad) does not contain FFh is a Bad Block. The Bad Block Information must be read before any erase is attempted as the Bad Block Information may be erased. For the system to be able to recognize the Bad Blocks based on the original information it is recommended to create a Bad Block table following the flowchart shown in Figure 22. The 1st block, which is placed on 00h block address is guaranteed to be a valid block.

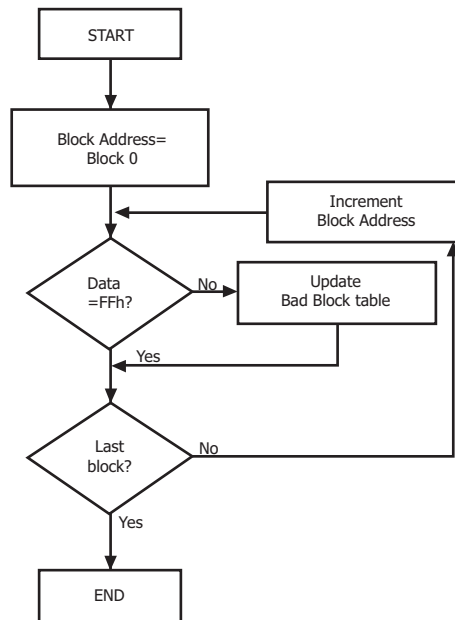
**Bad Replacement**

Over the lifetime of the device additional Bad Blocks may develop. In this case the block has to be replaced by copying the data to a valid block. These additional Bad Blocks can be identified as attempts to program or erase them will give errors in the Status Register.

As the failure of a page program operation does not affect the data in other pages in the same block, the block can be replaced by re-programming the current data and copying the rest of the replaced block to an available valid block. Refer to Table 18 for the recommended procedure to follow if an error occurs during an operation.

Operation	Recommended Procedure
Erase	Block Replacement
Program	Block Replacement or ECC (with 4bit/528byte)
Read	ECC (with 4bit/528byte)

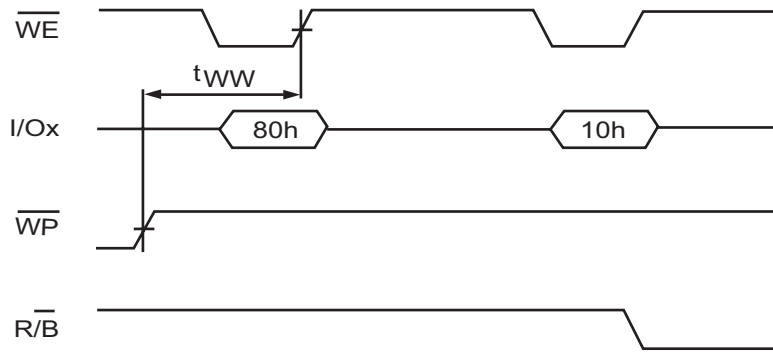
**Table 18: Block Failure**



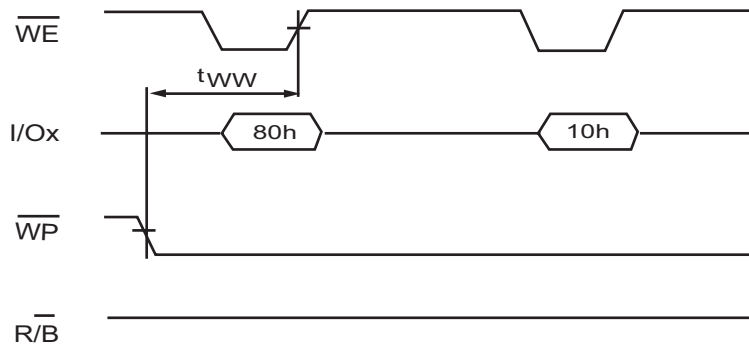
**Figure 22: Bad Block Management Flowchart**

## Write Protect Operation

The Erase and Program Operations are automatically reset when  $\overline{WP}$  goes Low ( $t_{WW} = 100\text{ns, min}$ ). The operations are enabled and disabled as follows (Figure 23~26)



**Figure 23: Enable Programming**



**Figure 24: Disable Programming**

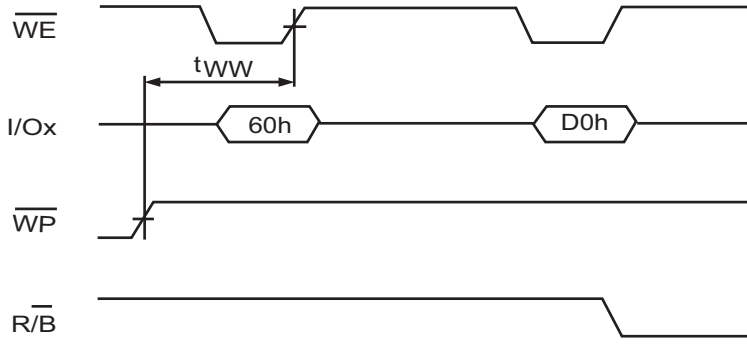


Figure 25: Enable Erasing

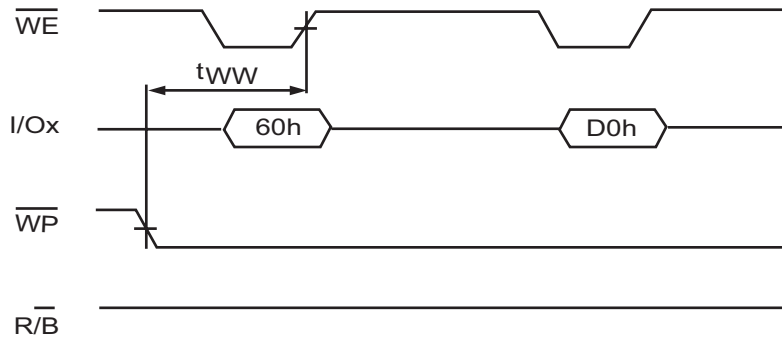
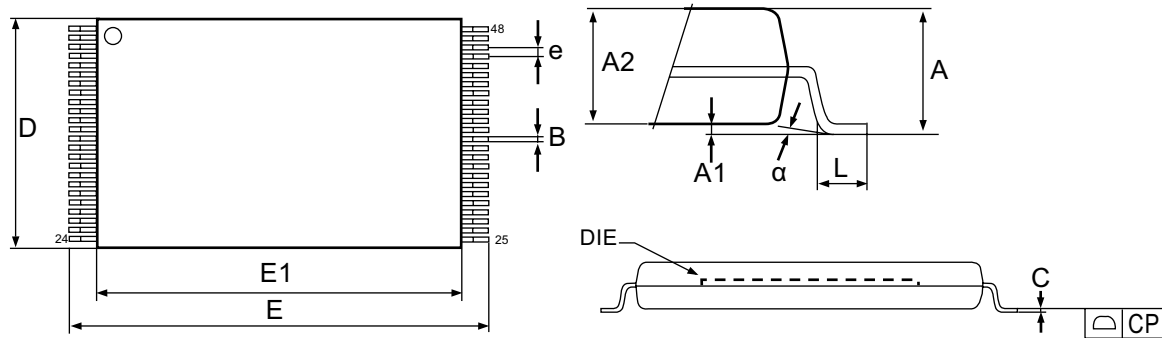


Figure 26: Disable Erasing

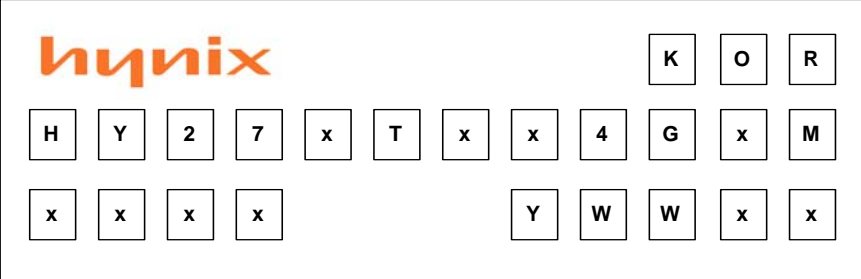


**Figure 27. 48-TSOP1 - 48-lead Plastic Thin Small Outline, 12 x 20mm, Package Outline**

Symbol	millimeters		
	Min	Typ	Max
A			1.200
A1	0.050		0.150
A2	0.980		1.030
B	0.170		0.250
C	0.100		0.200
CP			0.100
D	11.910	12.000	12.120
E	19.900	20.000	20.100
E1	18.300	18.400	18.500
e		0.500	
L	0.500		0.680
alpha	0		5

**Table 19: 48-TSOP1 - 48-lead Plastic Thin Small Outline,  
12 x 20mm, Package Mechanical Data**

**MARKING INFORMATION - TSOP1**

Packag	Marking Example
<b>TSOP1</b>	

- <b>hynix</b>	: Hynix Symbol
- <b>KOR</b>	: Origin Country
- <b>HY27xTxx4GxM xxxx</b>	: Part Number
<b>HY</b> : Hynix	
<b>27</b> : NAND Flash	
<b>x</b> : Power Supply	: U(2.7V ~ 3.6V)
<b>T</b> : Classification	: Multi Level Cell+Single Die+Large Block
<b>xx</b> : Bit Organization	: 08(x8), 16(x16)
<b>4G</b> : Density	: 4Gbit
<b>x</b> : Mode	: 2(1nCE & 1R/nB; Sequential Row Read Disable)
<b>M</b> : Version	: 1st Generation
<b>x</b> : Package Type	: T(48-TSOP1)
<b>x</b> : Package Material	: Blank(Normal), P(Lead Free)
<b>x</b> : Operating Temperature	: C(0°C ~ 70°C), E(-25°C ~ 85°C) M(-30°C ~ 85°C), I(-40°C ~ 85°C)
<b>x</b> : Bad Block	: B(Included Bad Block), S(1~5 Bad Block), P(All Good Block)
- <b>Y</b> : Year (ex: 5=year 2005, 06= year 2006)	
- <b>ww</b> : Work Week (ex: 12= work week 12)	
- <b>xx</b> : Process Code	
<b>Note</b>	
- <b>Capital Letter</b>	: Fixed Item
- <b>Small Letter</b>	: Non-fixed Item